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Keith B. Stobie et al.

Serial No.:

Not Yet Assigned

Att'y Docket No.: 13768.459

Filing Date:

November 26, 2003

For:

DYNAMICALLY TUNABLE SOFTWARE TEST

INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANTU.S. Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Issue Date</u>	<u>Name</u>
<u>ZW</u> 1	5,513,315	04/30/96	Tierney et al.
<u>ZW</u> 2	5,548,718	08/20/96	Siegel et al.
<u>ZW</u> 3	5,774,725	06/30/98	Yadav et al.
<u>ZW</u> 4	6,067,639	05/23/00	Rodrigues et al.
<u>ZW</u> 5	6,408,403	06/18/02	Rodrigues et al.
<u>ZW</u> 6	6,577,982	06/10/03	Erb

Other Documents

(including author, title, pertinent pages, etc.)

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<u>ZW</u> 9	P.D. Coward, "A Review of Software Testing", Information and Software Technology, Vol. 30, Issue 3, April 1988, pp. 189-98.

Examiner: /Zheng Wei/

Date Considered: 02/12/2007

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While the filing of Information Disclosure Statements is voluntary, the procedure is governed by the guidelines of Section 609 of the Manual of Patent Examining Procedure and 37 C.F.R. §§ 1.97 and 1.98. To be considered a proper Information Disclosure Statement, Form PTO-1449 shall be accompanied by a copy of each listed patent or publication or other item of information and a translation of the pertinent portions of foreign documents (if an existing translation is readily available to the applicant), an explanation of relevance of each reference not in the English language, and should be submitted in a timely manner as set out in MPEP Sec. 609.

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